

Source	Applies to	Change in \mathcal{A} or yield	Impact
Integrated luminosity	Simulated processes	2.3%	1.9%
Hadronic τ ID and trigger	Simulated processes	6–12%	1.5%
τ_h ES	Simulated processes	2–17%	<0.1%
Rate of e misidentified as τ_h	$Z/\gamma^* \rightarrow ee$	13–29%	0.4%
Rate of μ misidentified as τ_h	$Z/\gamma^* \rightarrow \mu\mu$	30%	0.2%
Electron ID and trigger	Simulated processes	2%	1.5%
e ES	Simulated processes	<1%	0.2%
Muon ID and trigger	Simulated processes	2%	1.6%
μ ES	Simulated processes	<1%	<0.1%
p_T^{miss} response and resolution	Simulated processes	1–10%	0.2%
Norm. $Z/\gamma^* \rightarrow ee, \mu\mu$	$Z/\gamma^* \rightarrow ee, \mu\mu$	Unconstrained	1.8%
Norm. and shape of false τ_h	$\tau_e \tau_h, \tau_\mu \tau_h, \tau_h \tau_h$ channels	6–16%	<0.1%
Norm. and shape of multijet	$\tau_e \tau_\mu, \tau_\mu \tau_\mu$ channels	20%	0.2%
Norm. $t\bar{t}$	$t\bar{t}$	7%	1.0%
Shape $t\bar{t}$	$t\bar{t}$	1–6%	<0.1%
Norm. SM H	SM H	30%	<0.1%
Norm. single top quark	Single top quark	15%	<0.1%
Norm. diboson	Diboson	15%	0.2%
Norm. W+jets	W+jets	15%	<0.1%
PDF	Signal	1%	1.0%
Scale dependence	Signal	<6%	0.5%
UE and PS	Signal	1%	1.0%